

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	4990	382/282,283,266,267,268,269,260,261,262,263,264,265,199.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:12
L2	384	((contour or edge or boundary or border) near6 (target or object)) and ((extract\$3 near5 pixel)) and ((measure\$3 or calculat\$3 or comput\$3) near5 (direction or vector) near6 pixel)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:28
L3	47	1 and 2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:13
L4	149	"382"/\$.ccls. and 2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:14
L5	505	((contour or edge or boundary or border) near6 (target or object)) and (extract\$3 near5 (pixel or pixil)) and ((measure\$3 or calculat\$3 or comput\$3 or determin\$3) near5 (direction or vector) near6 (pixel or pixil))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:15
L6	83	1 and 5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:15
L7	5	((((inspect\$3 or analy\$4 or determin\$3) near6 defect) near6 (contour or edge or boundary or border) near6 (target or object)) and (filter same size same (mask or extract\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:18
L8	17	((((inspect\$3 or analy\$4 or determin\$3) with defect) with (contour or edge or boundary or border) with (target or object)) and (filter same size same (mask or extract\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:19

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L9	24	((((inspect\$3 or analy\$4 or determin\$3) with defect) same (contour or edge or boundary or border) same (target or object)) and (filter same size same (mask or extract\$3)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:19
L10	26	((((inspect\$3 or analy\$4 or determin\$3) with (defect or flaw or fault)) same (contour or edge or boundary or border) same (target or object)) and (filter same size same (mask or extract\$3)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:21
L11	1	1 and 10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:20
L12	494	((((inspect\$3 or analy\$4 or determin\$3)) same (contour or edge or boundary or border) same (target or object)) and (filter same size same (mask or extract\$3)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:21
L13	47	1 and 12	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:21
L14	1	((inspect\$3 with contour with target with object) and (measur\$3 same direction same edge same pixel same angle same density same gradient) and (edge same pixel same sequentially same time same compar\$3 same direction)).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:30
L15	0	((inspect\$3 with contour with target with object) and (measur\$3 same direction same edge same pixel same angle same density same gradient) and (edge same pixel same sequentially same time same compar\$3 same direction) and (edge with cod\$3)) .clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:30

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L16	0	((inspect\$3 with contour with target with object) and (measur\$3 same direction same edge same pixel same angle same density same gradient) and (edge same pixel same time same direction) and (edge with cod\$3)) .clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:31
L17	1	((inspect\$3 with contour with target with object) and (measur\$3 same direction same edge same pixel same angle same density same gradient) and (edge same pixel same time same direction)) .clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/07 18:31

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» Key

IEEE JNL IEEE Journal or Magazine

IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

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- ☐ 1. **Extraction of straight lines in aerial images**
Venkateswar, V.; Chellappa, R.;
[Pattern Analysis and Machine Intelligence, IEEE Transactions on](#)
Volume 14, Issue 11, Nov. 1992 Page(s):1111 - 1114
Digital Object Identifier 10.1109/34.166627
[AbstractPlus](#) | Full Text: [PDF](#)(404 KB) IEEE JNL
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Sat, 7 Jul 2007, 6:24:55 PM EST

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- #1 (((contour or edge or boundary or border) <near/6> (target or object)) and ((extract* <near/5> pixel)) and ((measur* or calculat* or comput*) <near/5> (direction or vector) <near/6> pixel))<in>metadata)
- #2 (((contour or edge or boundary or border) <paragraph> (target or object)) and ((extract* <near/5> pixel)) and ((measur* or calculat* or comput*) <near/5> (direction or vector) <near/6> pixel))<in>metadata)

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Inventor Name Search Result

Your Search was:

Last Name = FUJIEDA

First Name = SHIRO

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>07988921</u>	Not Issued	164	03/12/1993	APPARATUS AND METHOD FOR DECIDING OR SETTING IDEAL LIGHTING CONDITIONS AND PHOTOGRAPHIC CONDITIONS, ETC., IN IMAGE PROCESSING SYSTEM, OR FOR AIDING IN DECIDING OR SETTING OF THE LIGHTING CONDITIONS	FUJIEDA, SHIRO
<u>09445304</u>	<u>7239740</u>	150	12/06/1999	IMAGE PROCESSING APPARATUS AND METHOD, MEDIUM STORING PROGRAM FOR IMAGE PROCESSING, AND INSPECTION APPARATUS	FUJIEDA, SHIRO
<u>09974539</u>	Not Issued	71	10/09/2001	CONTOUR INSPECTION METHOD AND APPARATUS	FUJIEDA, SHIRO
<u>09996417</u>	<u>6954550</u>	150	11/28/2001	IMAGE PROCESSING METHOD AND APPARATUS	FUJIEDA, SHIRO
<u>10681373</u>	<u>7212672</u>	150	10/09/2003	IMAGE PROCESSING APPARATUS AND IMAGE PROCESSING METHOD	FUJIEDA, SHIRO
<u>11373494</u>	Not Issued	30	03/13/2006	Image processing method, three-dimensional position measuring method and image processing apparatus	FUJIEDA, SHIRO
<u>11452433</u>	Not Issued	25	06/14/2006	Three-dimensional measuring method and three-dimensional measuring apparatus	FUJIEDA, SHIRO
<u>11454120</u>	Not Issued	25	06/16/2006	Image processing apparatus	FUJIEDA, SHIRO

Inventor Search Completed: No Records to Display.

	Last Name	First Name	
Search Another: Inventor	<input type="text" value="FUJIEDA"/>	<input type="text" value="SHIRO"/>	<input type="button" value="Search"/>

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